

Application/Control No.	Applicant(s)/Patent under Reexamination
10/748,156	TAMURA ET AL.
Examiner	Art Unit
Phung My Chung	2138

	SEARCHED				
Class	Subclass	Date	Examiner		
714	718	3/22/2006	РМС		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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(INCLUDING SE	ARCH STRATEG	Y)
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